

Claims

- [c1] In an integrated circuit chip having a programmable reference data table for holding information used to control at least one circuit block in said chip, a method of improving the performance of said chip comprising
 - (A) testing said chip to determine data comprising operating voltages at different clock speeds; and
 - (B) entering values based on said data into said reference data table.
- [c2] A method according to Claim 1 wherein said values are permanently entered into said reference data table.
- [c3] A method according to Claim 2 wherein said values are entered using an anti-fuse method.
- [c4] A method according to Claim 2 wherein said values are entered using a non-volatile memory method.
- [c5] A method according to Claim 1 wherein said values are tentatively entered into said reference data table.
- [c6] A method according to Claim 1 wherein said chip is for use in a battery-powered computer and is tested at 2 to 4 different supply voltages between 1 and 4 volts, 2 to 4 different back-bias voltages between -0.5 and +0.5 volts, and 2 to 4 different clock speeds between 1 and 300 MHz.
- [c7] A method according to Claim 1 wherein said chip is for use in a plug-in computer and is tested at 2 to 4 different supply voltages between 1 and 4 volts, 2 to 4 different back-bias voltages between -0.5 and +0.5 volts, and 2 to 4 different clock speeds between 0.2 and 2 GHz.
- [c8] A method according to Claim 1 wherein said chip has only a single circuit block.
- [c9] A method according to Claim 1 wherein said chip has numerous circuit blocks.
- [c10] A method according to Claim 1 wherein said chip is tested when it is on a wafer.
- [c11] A method according to Claim 1 wherein said chip is tested after it has been cut

from a wafer.

- [c12] A method according to Claim 1 wherein said data comprises at least one supply voltage, at least one back-bias voltage, and at least one clock rate.
- [c13] A method according to Claim 1 wherein said data comprises the minimum supply voltages and minimum back bias voltages at which the chip successfully executed a program at different clock speeds.
- [c14] A method according to Claim 1 wherein said data comprises at least one supply voltage, at least one back-bias voltage, at least one clock rate, at least one data bus width, or at least one power latency value.
- [c15] A method according to Claim 1 wherein the performance that is improved is the operating clock speed.
- [c16] A method according to Claim 1 wherein the performance that is improved is the operating voltage range.
- [c17] A microprocessor chip made according to the method of Claim 1.
- [c18] An integrated circuit chip made according to the method of Claim 1.
- [c19] A computer comprising an integrated circuit chip according to Claim 18.
- [c20] A computer according to Claim 19 that is battery powered.
- [c21] In a wafer having a multiplicity of integrated circuit chips thereon, each having a programmable reference data table for holding data including the supply voltage, back-bias voltage, and clock speed to be used to control at least one circuit block on said integrated circuit chip, a method of programming the reference data table of a chip with improved values comprising
 - (A) testing the chip to determine data comprising at least a minimum supply voltage and a minimum back-bias voltage at which said chip can operate at at least one clock speed; and
 - (B) based on said data, entering values into the chip's programmable reference data table comprising a supply voltage and back-bias voltage to be used to attain said at least one clock speed.

- [c22] An integrated circuit chip made according to the method of Claim 21.
- [c23] A computer comprising an integrated circuit chip according to Claim 22.
- [c24] In a wafer having a multiplicity of integrated circuit chips thereon, each of said chips having a programmable reference data table for holding, for at least one circuit block in said chip, values comprising supply voltages and back-bias voltages to be used to attain at least two different clock speeds, a method of improving the power usage requirements of said chip comprising
- (A) executing at least one program on said chip at at least two different supply voltages, at least two different back-bias voltages, and at least two different clock speeds;
 - (B) collecting data comprising the lowest supply voltage and the lowest back-bias voltage at which said chip successfully executed said program at each clock speed tested;
 - (C) based on said data, determining values comprising the optimal supply voltages and back bias voltages to be used for at least two different clock speeds; and
 - (D) entering said values into said table.
- [c25] A wafer having at least one chip thereon programmed according to the method of Claim 24.

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